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| Notice of References Cited | Application/Control No. 10/757,442 | Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL. | |
| | Examiner William C. Dowling | Art Unit 2851 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,741,295 | 05-2004 | Nieuwenhuizen et al. | 348/687 |
| | B | US-2003/0086026 | 05-2003 | Kim, Jong-dae | 348/806 |
| | C | US-6,002,454 | 12-1999 | Kajiwara et al. | 348/806 |
| | D | US-5,532,765 | 07-1996 | Inoue et al. | 348/807 |
| | E | US-5,519,447 | 05-1996 | Shima et al. | 348/556 |
| | F | US-5,298,985 | 03-1994 | Tsujihara et al. | 348/745 |
| | G | US-5,200,815 | 04-1993 | Tsujihara et al. | 348/181 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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